

12. (Amended) A method for measuring, comprising the steps of:

positioning a measuring device on a drawing, said measuring device having a first set of indicia corresponding to a first, actual linear scale and a second set of indicia corresponding to a second, non-actual linear scale, wherein said drawing has features sized in said second, non-actual linear scale;

using said second set of indicia, determining a first, non-actual length measurement of a feature on said drawing;

using said first set of indicia, determining a second, actual length measurement on an object, wherein said first, non-actual length measurement and said second, actual length measurement correspond to the same actual dimension.

## **REMARKS**

### **I. Introduction**

Claims 1 to 12 are pending in the present application. In view of the foregoing amendments and the following remarks, it is respectfully submitted that all of the presently pending claims are allowable, and reconsideration is respectfully requested.

Applicants note with appreciation the acknowledgment that the drawings filed on February 2, 2003, are accepted.

### **II. Rejection of Claims 1 to 9 Under 35 U.S.C. § 102(b)**

Claims 1 to 9 were rejected under 35 U.S.C. 102(b) as anticipated by U.S. Patent No. 5,251,382 ("Hellar"). Applicants respectfully submit that Hellar does not anticipate the present claims for the following reasons.

Claim 1 relates to a measuring device that includes a first edge defining a first region. Claim 1 recites that the first region has a first set of indicia corresponding to a first linear scale, the first linear scale being actual. Claim 1 also recites that the measuring device includes a second edge defining a second region, the second region having a second set of indicia corresponding to a second linear scale. Claim 1 recites that the second linear scale is non-actual. Claim 1 has been amended to recite that a